

Corrigendum

Corrigendum to “A New Method of Scanning Tunneling Spectroscopy for Study of the Energy Structure of Semiconductors and Free Electron Gas in Metals”

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In the article titled “A New Method of Scanning Tunneling Spectroscopy for Study of the Energy Structure of Semiconductors and Free Electron Gas in Metals” [1], the authors identified an error in Equation (3), which should be corrected as follows:

Original text

$$I_t \propto \frac{1}{l} \left(E_{gn} \exp \left(\xi \frac{eV - eV_{SPV}}{E_{gn}} \right) - E_{gp} \exp \left(\xi \frac{-eV - eV_{SPV}}{E_{gp}} \right) \right) \quad (3)$$

The corrected formula (3):

$$I_t \propto \frac{1}{l} \left(E_{gn} \exp \left(\xi \frac{eV - eV_{SPV}}{E_{gn}} \right) - E_{gp} \exp \left(\xi \frac{-(eV - eV_{SPV})}{E_{gp}} \right) \right) \quad (3)$$

References

- [1] A. Pavlov and H. Ihantola, “A New Method of Scanning Tunneling Spectroscopy for Study of the Energy Structure of Semiconductors and Free Electron Gas in Metals,” *The Journal of Scanning Microscopies*, vol. 19, no. 7, pp. 459–465, 2006.